

**Search Notes**

Application/Control No.

10/037,755

Examiner

Erin M. File

Applicant(s)/Patent under  
Reexamination

CHO ET AL.

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	130	11/6/2006	EMF
375	140	11/6/2006	EMF
375	141	11/6/2006	EMF
375	146	11/6/2006	EMF
370	208	11/6/2006	EMF
370	209	11/6/2006	EMF
370	329	11/6/2006	EMF
370	335	11/6/2006	EMF
370	341	11/6/2006	EMF
370	342	11/6/2006	EMF
370	431	11/6/2006	EMF
370	441	11/6/2006	EMF
370	491	11/6/2006	EMF
370	500	11/6/2006	EMF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	11/6/2006	EMF
PLUS Search	11/6/2006	EMF